



Spot Check Evaluation

APPLICANT : Sun Cupid Technology (HK) Ltd.
EQUIPMENT : 5G Smartphone
BRAND NAME : NUU
MODEL NAME : S6707X
MARKETING NAME : NUU X10 5G, X10 5G
FCC ID : 2ADINS6707XN
STANDARD : 47 CFR Part 22(H), 24(E), 27(L), 27(M), 27(D), 27(H),
27(F), 27(N), 27(O), 27(Q), 90(S), 96
47 CFR Part 15 Subpart C §15.247
47 CFR Part 15 Subpart E §15.407
TEST DATE(S) : Apr. 14, 2026 ~ Apr. 23, 2026

We, Sporton International Inc. (ShenZhen), would like to declare that the tested sample has been evaluated in accordance with the test procedures and has been in compliance with the applicable technical standards.

The test results in this report apply exclusively to the tested model / sample. Without written approval of Sporton International Inc. (ShenZhen), the test report shall not be reproduced except in full.

Fly Liang

Approved by: Fly Liang



Sporton International Inc. (ShenZhen)

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People's Republic of China



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REVISION HISTORY

REPORT NO.	VERSION	DESCRIPTION	ISSUED DATE
471902-02	Rev. 01	Initial issue of report	May 07, 2026

Conformity Assessment Condition:

1. The test results (PASS/FAIL) with all measurement uncertainty excluded are presented against the regulation limits or in accordance with the requirements stipulated by the applicant/manufacture who shall bear all the risks of non-compliance that may potentially occur if measurement uncertainty is taken into account.
2. The measurement uncertainty please refer to each test result in the section "Measurement Uncertainty"

Disclaimer:

The product specifications of the EUT presented in the test report that may affect the test assessments are declared by the manufacturer who shall take full responsibility for the authenticity.



1 General Description

1.1 Applicant

Sun Cupid Technology (HK) Ltd.

16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.

1.2 Manufacturer

Suncupid (ShenZhen) Electronic Ltd.

Baolong Industrial City, Longgang District, ShenZhen Hi-Tech Road, Building 1, A7, China.

1.3 Product Feature of Equipment Under Test

Product Feature	
Equipment	5G Smartphone
Brand Name	NUU
Model Name	S6707X
Marketing Name	NUU X10 5G, X10 5G
FCC ID	2ADINS6707XN
IMEI Code	Conducted: 350915160111824 for BT/WIFI 350915160111212 for WWAN Radiation: 350915160112541
HW Version	V01
SW Version	S6707X-AM-W-MV12804-01.I
EUT Stage	Identical Prototype

1.4 Modification of EUT

No modifications are made to the EUT during all test items.

1.5 Testing Site

Sporton International Inc. (ShenZhen) is accredited to ISO/IEC 17025:2017 by American Association for Laboratory Accreditation with Certificate Number 5145.01.

Test Firm	Sporton International Inc. (ShenZhen)		
Test Site Location	101, 1st Floor, Block B, Building 1, No. 2, Tengfeng 4th Road, Fenghuang Community, Fuyong Street, Baoan District, Shenzhen City, Guangdong Province 518103 People's Republic of China TEL: +86-755-86066985		
Test Site No.	Sporton Site No.	FCC Designation No.	FCC Test Firm Registration No.
	TH01-SZ 03CH03-SZ 03CH01-SZ	CN1256	421272

1.6 Test Software

Item	Site	Manufacturer	Name	Version
1.	03CH01-SZ	AUDIX	E3	6.2009-8-24
2.	03CH03-SZ	AUDIX	E3	6.2009-8-24

1.7 Applicable Standards

According to the specifications of the manufacturer, the EUT must comply with the requirements of the following standards:

- ♦ FCC KDB 484596 D01 Referencing Test Data v03
- ♦ 47 CFR Part 22(H), 24(E), 27(L), 27(M), 27(D), 27(H), 27(F), 27(N), 27(O), 27(Q), 90(S), 96
- ♦ 47 CFR Part 15 Subpart C §15.247
- ♦ 47 CFR Part 15 Subpart E §15.407
- ♦ ANSI C63.10-2020+Cor.1-2023
- ♦ ANSI C63.26-2015



2 Re-use of Measured Data

2.1 Introduction Section

This application re-uses data collected on a similar device. The subject device of this application (Model: S6707X, FCC ID: 2ADINS6707XN) is electrically identical to the reference device (Model: S6707X, FCC ID: 2ADINS6707X) for the portions of the circuitry corresponding to the data being re-used, following the FCC KDB 484596 D01 Referencing Test Data v03.

ECR Data Referencing Inquiry has been approved by TCB, and the data referencing and spot check test plan includes RF/EMC, the details are presented in section 2.3 of this report, and for SAR Reference detail, please refer to FCC SAR report FA471902-02.

The criteria set in section 3 of KDB 484596 D01 v03 is followed to determine whether the data referencing is justified. For SAR, the higher between the referenced value and the spot check value is used to determine compliance in both standalone and simultaneous transmission conditions

The applicant takes full responsibility that the test data as referenced in this report represent compliance for this FCC ID: 2ADINS6707XN .

2.2 Model Difference Information

The **main** difference between FCC ID: 2ADINS6707X and FCC ID: 2ADINS6707XN is as below:

- Added an NFC chip to the mainboard and an NFC antenna to the middle frame.

Other differences and all the details of similarity and difference can be found in the confidential documents (Product Equality Declaration).



2.3 Reference detail Section:

Rule Part	Equipment Class	Frequency Band (MHz)	Reference FCC ID (Parent)	Reference on test	Reference Title	FCC ID Filling (Variant)	Test on the variant	Data Referencing (Y/N)
15C	DSS (BR/EDR)	2400~2483.5	2ADINS6707X	Full test	FR471902A	2ADINS6707XN	Spot check	Y, All test items
	DTS (BLE)	2400~2483.5	2ADINS6707X	Full test	FR471902B	2ADINS6707XN	Spot check	Y, All test items
	DTS (WLAN)	2400~2483.5	2ADINS6707X	Full test	FR471902C	2ADINS6707XN	Spot check	Y, All test items
15E	U-NII	5180~5240	2ADINS6707X	Full test	FR471902D	2ADINS6707XN	Spot check	Y, All test items
		5260~5320	2ADINS6707X	Full test	FR471902D	2ADINS6707XN	Spot check	Y, All test items
		5500~5720	2ADINS6707X	Full test	FR471902D	2ADINS6707XN	Spot check	Y, All test items
		5745~5825	2ADINS6707X	Full test	FR471902D	2ADINS6707XN	Spot check	Y, All test items
		5260~5320 5500~5720	2ADINS6707X	Full test	FZ471902	2ADINS6707XN	Spot check	Y, All test items
22, 24, 27, 90, 96,	PCE (GSM/WC DMA)	GSM850/1900 WCDMA B2/4/5	2ADINS6707X	Full test	FG471902A	2ADINS6707XN	Spot check	Y, All test items
	PCE (LTE)	LTE B2/4/5/7/12/13/17/25/26/30/66/71	2ADINS6707X	Full test	FG471902B FG471902C FG471902D FG471902E FG471902H	2ADINS6707XN	Spot check	Y, All test items
	CBE (LTE)	LTE B48	2ADINS6707X	Full test	FG471902F FG471902G	2ADINS6707XN	Spot check	Y, All test items
	PCE (NR)	5G NR n2/5/7/25/30/38/41/66/71/77/78	2ADINS6707X	Full test	FG471902I FG471902J FG471902K FG471902O FG471902N	2ADINS6707XN	Spot check	Y, All test items
	CBE (NR)	5G NR n48/77/78	2ADINS6707X	Full test	FG471902L FG471902M	2ADINS6707XN	Spot check	Y, All test items

Y: Pointer to spot-check exhibit; N: Pointer to full test exhibit

2.4 Spot Check Verification Data Section

All test items test against the variant model based on the worst-case condition from the original model was performed in this filing to demonstrate the test data from original model remains representative for the variant model.

All test procedures follow the related section of parent report.

Spot-check measurements, while being always compliant with the applicable rule part(s) for the test under consideration, show a deviation d_{dB} from the reference data no larger than 3 dB:

$$d_{dB} = |V_{dB} - R_{dB}| \leq 3 \text{ dB} \quad (1)$$

V_{dB} , the variant spot-check level

R_{dB} , the corresponding measurement level for the reference model

An alternative to the limit of eq. (1) is available, and is based on considering how far the reference data R_{dB} is from the compliance threshold C_{dB} (also expressed in dB), for the particular test under consideration. In this case, if $M_{dB} = |C_{dB} - R_{dB}|$ is the margin in dB from the compliance limit, a spot check may be considered acceptable when the deviation d_{dB} from the reference data satisfies the following condition:

$$d_{dB} = |V_{dB} - R_{dB}| \leq (3 + M_{dB} / 20) \text{ dB} , \text{ for } 0 \leq M_{dB} \leq 60 \text{ dB} \quad (2)$$

$$d_{dB} = |V_{dB} - R_{dB}| = 6 \text{ dB} , \text{ for } M_{dB} > 60 \text{ dB}$$

where “| |” is the absolute value of the measured quantity.

When using the option in eq. (2), d_{dB} increases linearly from 3 dB to 6 dB.



Summary for spot check for each rule entry and technology is listed as below:

Mode	Test Item (Unit)	2ADINS6707X Parent Worst mode Test Result	2ADINS6707XN Variant Check Test Result	Deviation	Limit
BT 1Mbps (DH5-CH78)	Number of Channels (N)	79	79	0	3
	Hopping Channel Separation (MHz)	0.999	0.981	0.018	3
	Dwell Time of Each Channel(s)	0.31	0.31	0	3
	20dB Bandwidth(MHz)	0.865	0.861	0.004	3
	99% Bandwidth(MHz)	0.757	0.749	0.008	3
	Conducted Band Edges(dBm)	-51.67	-50.87	0.8	3
	Conducted Spurious Emission(dBm)	-33.27	-35.72	2.45	3
	Radiated Band Edges and Radiated Spurious Emission (dBuV/m)	57.98	55.23	2.75	3
	AC Conducted Emission (dBuV)	-4.09	-6.81	2.72	3
BLE (1M-CH39)	6dB Bandwidth (MHz)	0.694	0.708	0.014	3
	99% Bandwidth (MHz)	1.031	1.035	0.004	3
	Power Spectral Density (dBm/3KHz)	-17.71	-18.34	0.63	3
	Conducted Band Edges and Spurious Emission (dBm)	-51.98	-51.16	0.82	3
	Conducted Spurious Emission (dBm)	-42.96	-45.89	2.93	3
	Radiated Band Edges and Spurious Emission (dBuV/m)	42.68	44.41	1.73	3
	AC Conducted Emission (dBuV)	-4.09	-6.81	2.72	3
WLAN 2.4G (802.11n HT40)	6dB Bandwidth (MHz)	10.1	9.48	0.62	3
	99% Bandwidth (MHz)	15.518	14.454	1.064	3
	Power Spectral Density (dBm/3KHz)	-2.22	-3.41	1.19	3
	Conducted Band Edges and Spurious Emission (dBm)	-19.69	-21.03	1.34	3
	Conducted Spurious Emission (dBm)	-43.21	-45.21	2	3
	Radiated Band Edges and Spurious Emission (dBuV/m)	50.66	49.45	1.21	3
WLAN 2.4G	AC Conducted Emission (dBuV)	-4.09	-6.81	2.72	3



Mode	Test Item (Unit)	2ADINS6707X Parent Worst mode Test Result	2ADINS6707XN Variant Check Test Result	Deviation	Limit
WLAN 5G	26dB & 99% Occupied Bandwidth (MHz)	26.82	25.8	1.02	3
	Power Spectral Density (dBm/MHz)	9.69	8.99	0.7	3
	Radiated Band Edges and Spurious Emission (dBuV/m)	50.97	50.88	0.09	3
	AC Conducted Emission (dBuV)	-4.09	-6.71	2.62	3
	DFS (s)	0.90923	0.956832	0.047602	3

Mode	Test Item (Unit)	2ADINS6707X Parent Worst mode Test Result	2ADINS6707XN Variant Check Test Result	Deviation	Limit
WWAN Conducted LTE B26	26dB Bandwidth (MHz)	2.96	2.99	0.03	3
	Peak-to-Average Ratio (dB)	5.16	4.90	0.26	3
	Occupied Bandwidth (MHz)	2.73	2.70	0.03	3
	Conducted Band Edge Measurement (dBm)	-13.15	-14.22	1.07	3
	Conducted Spurious Emission (dBm)	-38.86	-39.27	0.41	3
	Frequency Stability Temperature & Voltage (ppm)	0.0022	0.0028	0.0006	3

Test Item	Mode	2ADINS6707X Parent Worst mode Test Result	2ADINS6707XN Variant Check Test Result	Deviation (dB)	Deviation Limit (dB)
WWAN Radiated Spurious Emission(dBm)	GSM 850	-50.68	-49.81	0.87	3
	WCDMA B4	-54.30	-55.18	0.88	3
	LTE B48	-49.7	-50.22	0.52	3
	5G NR n77	-52.07	-50.72	1.35	3



Test Item	Mode	2ADINS6707X Parent Worst mode Test Result	2ADINS6707XN Variant Check Test Result	Deviation (dB)	Deviation Limit (dB)
Conducted Power (dBm)	BT BR/EDR	8.5	8	0.5	3
	BLE 1Mbps	-3.1	-3.1	0	3
	11b, 2.4GHz	20.4	20.3	0.1	3
	11g, 2.4GHz	17.8	17.8	0	3
	11n HT20, 2.4GHz	17.9	17.8	0.1	3
	11n HT40, 2.4GHz	15.9	15.9	0	3
	11a, 5.5GHz	20.49	20.03	0.46	3
	11n HT20, 5.5GHz	18.90	18.87	0.03	3
	11n HT40, 5.5GHz	17.96	17.80	0.16	3
	11ac VHT80, 5.5GHz	16.59	16.56	0.03	3
	LTE B26	23.76	23.44	0.32	3
	5G NR n25	24.32	23.31	1.01	3
	DC_66A_n25A	23.18	22.69	0.49	3
	5G NR n2	24.16	23.32	0.84	3
	DC_5A_n2A	24.09	23.31	0.78	3
	5G NR n5	24.25	24.12	0.13	3
	DC_2A_n5A	24.09	24.05	0.04	3
	5G NR n7	22.88	22.18	0.7	3
	5G NR n30	23.1	22.6	0.5	3
	5G NR n41	24.99	24.49	0.5	3
	DC_2A_n41A	24.85	24.36	0.49	3
	5G NR n38	22.32	22.05	0.27	3
	5G NR n66	24.27	23.21	1.06	3
	DC_2A_n66A	24.18	23.16	1.02	3
	DC_30A_n66A	23.04	22.68	0.36	3
	5G NR n71	23.81	23.75	0.06	3
	DC_2A_n71A	23.26	22.96	0.3	3
	5G NR n77(Part27O)	26.63	26.27	0.36	3
	DC_2A_n77A(Part27O)	26.53	25.66	0.87	3
	5G NR n78(Part27O)	26.27	26.24	0.03	3
	5G NR n77(Part27Q)	26.66	26.17	0.49	3
	DC_2A_n77A(Part27Q)	26.59	25.68	0.91	3
	5G NR n78(Part27Q)	26.25	26.11	0.14	3
	5G NR n77(Part96)	23.81	20.97	2.84	3
	DC_2A_n77A(Part96)	23.71	20.95	2.76	3
	5G NR n48(Part96)	22.7	20.21	2.49	3
	5G NR n78(Part96)	23.63	20.83	2.8	3



Conclusion:

All test items test against the variant model based on the worst-case condition from the original model was performed in this filing to demonstrate the test data from original model remains representative for the variant model.

Based on the spot check test result, the test data from the original model is representative for the variant model. All spot check test data are shown within expected level compliant to limit line.

We are using power and ERP/EIRP measurements from the original parent model reports to list on the grant.

We confirm that the test data referencing policy of FCC KDB 484596 D01 Referencing Test Data v03 has been followed and the test data as referenced from the parent model report represents compliance with new FCC ID.



3 List of Measuring Equipment

For BT/WIFI:

Instrument	Manufacturer	Model No.	Serial No.	Characteristics	Calibration Date	Test Date	Due Date	Remark
Spectrum Analyzer	R&S	FSV40	101078	10Hz~40GHz	Mar. 26, 2026	Apr. 20, 2026	Mar. 25, 2027	Conducted (TH01-SZ)
Pulse Power Sensor	Anritsu	MA2411B	1339473	30MHz~40GHz	Dec. 24, 2025	Apr. 20, 2026	Dec. 23, 2026	Conducted (TH01-SZ)
Power Meter	Anritsu	ML2495A	1218010	50MHz Bandwidth	Oct.13, 2025	Apr. 20, 2026	Oct. 12, 2026	Conducted (TH01-SZ)
EMI Test Receiver&SA	KEYSIGHT	N9038A	MY54450083	20Hz~8.4GHz	Apr. 02, 2026	Apr. 17, 2026	Apr. 01, 2027	Radiation (03CH03-SZ)
EXA Signal Analyzer	KEYSIGHT	N9010B	MY59071191	10KHz~44GHz	Mar. 27, 2026	Apr. 17, 2026	Mar. 26, 2027	Radiation (03CH03-SZ)
Loop Antenna	R&S	HFH2-Z2E	101141	9kHz~30MHz	Dec. 25, 2025	Apr. 17, 2026	Dec. 24, 2026	Radiation (03CH03-SZ)
Bilog Antenna	TeseQ	CBL6112D	35408	30MHz~2GHz	Sep. 13, 2025	Apr. 17, 2026	Sep. 12, 2026	Radiation (03CH03-SZ)
Double Ridge Guide Antenna	ETS-Lindgren	Burgeon-3117	00240107	1GHz~18GHz	Jul. 13, 2025	Apr. 17, 2026	Jul.12, 2026	Radiation (03CH03-SZ)
HF Amplifier	MITEQ	TTA1840-35-HG	1871923	18GHz~40GHz	Jul. 03, 2025	Apr. 17, 2026	Jul.02, 2026	Radiation (03CH03-SZ)
SHF-EHF Horn	com-power	AH-840	101071	18GHz~40GHz	Apr. 03, 2025	Apr. 17, 2026	Apr. 02, 2027	Radiation (03CH03-SZ)
Amplifier	EM Electronics	EM330	060756	0.01Hz ~3000MHz	Apr. 02, 2026	Apr. 17, 2026	Apr. 01, 2027	Radiation (03CH03-SZ)
HF Amplifier	MITEQ	AMF-7D-0010 1800-30-10P-R	1943528	1GHz~18GHz	Oct. 13, 2025	Apr. 17, 2026	Oct. 12, 2026	Radiation (03CH03-SZ)
HF Amplifier	Keysight	83017A	MY53270357	500MHz~26.5GHz	Apr. 02, 2026	Apr. 17, 2026	Apr. 01, 2027	Radiation (03CH03-SZ)
AC Power Source	Chroma	61601	616010002729	N/A	Oct. 13, 2026	Apr. 17, 2026	Oct. 12, 2027	Radiation (03CH03-SZ)
Turn Table	EM	EM1000	N/A	0~360 degree	NCR	Apr. 17, 2026	NCR	Radiation (03CH03-SZ)
Antenna Mast	EM	EM1000	N/A	1 m~4 m	NCR	Apr. 17, 2026	NCR	Radiation (03CH03-SZ)

NCR: No Calibration Required.



For WWAN Bands:

Instrument	Manufacturer	Model No.	Serial No.	Characteristics	Calibration Date	Test Date	Due Date	Remark
Spectrum Analyzer	R&S	FSV40	101078	10Hz~40GHz	Mar. 26, 2026	Apr. 14, 2026~ Apr. 23, 2026	Mar. 25, 2027	Conducted (TH01-SZ)
DC Power Supply	TTI	PL330P	290070	Max 32V , 3A	Oct.13,2025	Apr. 14, 2026~ Apr. 23, 2026	Oct. 12, 2026	Conducted (TH01-SZ)
Power Divider	Titan	P02N00518 0	923402	0.4GHz~26.5GHz	Nov. 07, 2025	Apr. 14, 2026~ Apr. 23, 2026	Nov. 06, 2026	Conducted (TH01-SZ)
Power Divider	TOJOIN	PS-2SM-04 265	60.06.020.007 7	0.4GHz~26.5GHz	Dec. 24, 2025	Apr. 14, 2026~ Apr. 23, 2026	Dec. 23, 2026	Conducted (TH01-SZ)
EMI Test Receiver&SA	Agilent	N9038A	MY52260185	20Hz~26.5GHz	Dec. 24, 2025	Apr. 18, 2026	Dec. 23, 2026	Radiation (03CH01-SZ)
Loop Antenna	R&S	HFH2-Z2E	101141	9kHz~30MHz	Dec. 26, 2025	Apr. 18, 2026	Dec. 25, 2026	Radiation (03CH01-SZ)
HF Amplifier	KEYSIGHT	83017A	MY53270105	0.5GHz~26.5GHz	Oct. 13,2025	Apr. 18, 2026	Oct. 12,2026	Radiation (03CH01-SZ)
Bilog Antenna	TeseQ	CBL6112D	35407	30MHz-2GHz	Dec. 23, 2025	Apr. 18, 2026	Dec. 22, 2026	Radiation (03CH01-SZ)
Double Ridge Horn Antenna	ETS-Lindgren	3117	00119436	1GHz~18GHz	Jul. 16, 2025	Apr. 18, 2026	Jul. 15, 2026	Radiation (03CH01-SZ)
SHF-EHF Horn	com-power	AH-840	101071	18GHz-40GHz	Apr. 03, 2025	Apr. 18, 2026	Apr. 02, 2027	Radiation (03CH01-SZ)
LF Amplifier	EM Electronics	EM330	060788	20MHz-3GHz	Dec. 24, 2025	Apr. 18, 2026	Dec. 23, 2026	Radiation (03CH01-SZ)
HF Amplifier	MITEQ	AMF-7D-00 101800-30-1 NP-P	1943528	1GHz~18GHz	Oct. 13, 2025	Apr. 18, 2026	Oct. 12, 2026	Radiation (03CH01-SZ)
HF Amplifier	MITEQ	TTA1840-35 -HG	1871923	18GHz~40GHz	Jul. 02, 2025	Apr. 18, 2026	Jul. 01, 2026	Radiation (03CH01-SZ)
AC Power Source	Chroma	61601	616010001985	N/A	Oct. 14, 2025	Apr. 18, 2026	Oct. 13, 2026	Radiation (03CH01-SZ)
Turn Table	EM	EM1000	N/A	0~360 degree	NCR	Apr. 18, 2026	NCR	Radiation (03CH01-SZ)
Antenna Mast	EM	EM1000	N/A	1 m~4 m	NCR	Apr. 18, 2026	NCR	Radiation (03CH01-SZ)

NCR: No Calibration Required.

4 Measurement Uncertainty

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI 63.26-2015. All the measurement uncertainty value were shown with a coverage K=2 to indicate 95% level of confidence. The measurement data show herein meets or exceeds the CISPR measurement uncertainty values specified in CISPR 16-4-2 and can be compared directly to specified limit to determine compliance.

Uncertainty of Conducted Measurement

Test Item	Uncertainty
Conducted Power	± 1.34 dB

03CH03-SZ(BT/WIF):

Uncertainty of Radiated Emission Measurement (30 MHz ~ 1000 MHz)

Measuring Uncertainty for a Level of Confidence of 95% ($U = 2Uc(y)$)	5.0 dB
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Uncertainty of Radiated Emission Measurement (1 GHz ~ 18 GHz)

Measuring Uncertainty for a Level of Confidence of 95% ($U = 2Uc(y)$)	4.9dB
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Uncertainty of Radiated Emission Measurement (18 GHz ~ 40 GHz)

Measuring Uncertainty for a Level of Confidence of 95% ($U = 2Uc(y)$)	5.0 dB
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03CH01-SZ(WWAN):

Uncertainty of Radiated Emission Measurement (30 MHz ~ 1000 MHz)

Measuring Uncertainty for a Level of Confidence of 95% ($U = 2Uc(y)$)	2.48 dB
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Uncertainty of Radiated Emission Measurement (1 GHz ~ 18 GHz)

Measuring Uncertainty for a Level of Confidence of 95% ($U = 2Uc(y)$)	3.53 dB
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Uncertainty of Radiated Emission Measurement (18 GHz ~ 40 GHz)

Measuring Uncertainty for a Level of Confidence of 95% ($U = 2Uc(y)$)	4.02 dB
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-THE END-